

Search Notes

Application/Control No.

10/667,364

Examiner

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Applicant(s)/Patent under
Reexamination

WON, JONG-EUN

Art Unit

2111

SEARCHED

Class	Subclass	Date	Examiner
710	301- 304,100,6 2,2,74	10/31/2005	GCR
713	400	10/31/2005	GCR
326	8	10/31/2005	GCR
714	5,7	10/31/2005	GCR
711	115	10/31/2005	GCR
361	684,685	10/31/2005	GCR

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
WEST: USPT, US OCR, EPO ABS, JPO ABS, DWPI, IBM TDB (see search history printouts)	10/31/2005	GCR
EAST: USPT (see search history printouts)	10/31/2005	GCR
NPL: IEEE Xplore (see search history printouts)	10/31/2005	GCR

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner